Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/809,725	CHAN, FRANK A.
Examiner	Art Unit

3736

Rene Towa

SEARCHED					
Class	Subclass	Date	Examiner		
600	573	4/13/2006	RTT		
600	576	4/13/2006	RTT		
600	583	4/13/2006	RTT		
606	181	4/13/2006	RTT		
606	182	4/13/2006	RTT		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
SEE SEARCH HISTORY	4/13/2006	RTT	
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